

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	(716/21).ccls. and (systematic adj defect\$2) and (circuit adj layout) and (feature adj vector\$2) and (index adj process\$3) and (defect adj region\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:16
L2	0	(716/19).ccls. and (systematic adj defect\$2) and (circuit adj layout) and (feature adj vector\$2) and (index adj process\$3) and (defect adj region\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:16
L3	0	(716/4).ccls. and (systematic adj defect\$2) and (circuit adj layout) and (feature adj vector\$2) and (index adj process\$3) and (defect adj region\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:16
L4	0	(716/5).ccls. and (systematic adj defect\$2) and (circuit adj layout) and (feature adj vector\$2) and (index adj process\$3) and (defect adj region\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:16
L5	0	("716"/\$).ccls. and (systematic adj defect\$2) and (circuit adj layout) and (feature adj vector\$2) and (index adj process\$3) and (defect adj region\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:16
L6	1	(382/145).ccls. and (systematic adj defect\$2) and (circuit adj layout) and (feature adj vector\$2) and (index adj process\$3) and (defect adj region\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:17
L7	2	(systematic adj defect\$2) and (circuit adj layout) and (feature adj vector\$2) and (index adj process\$3) and (defect adj region\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:18
L8	1	((systematic adj defect\$2) and (circuit adj layout) and (feature adj vector\$2) and (index adj process\$3) and (defect adj region\$2)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:18
L9	2	(systematic adj defect\$2) and (circuit adj layout) and (feature adj vector\$2) and (index adj process\$3) and (defect adj (region\$2 or area\$2 or zone\$2))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:47

EAST Search History

L10	0	(systematic adj defect\$2) and (circuit adj design) and (feature adj vector\$2) and (defeat adj vector\$2) and (index adj process\$3) and (defect adj (region\$2 or area\$2 or zone\$2)) and (bas\$3 adj pattern\$2) and (window adj grid)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:42
L11	0	(systematic adj defect\$2) and (circuit adj layout) and (feature adj vector\$2) and (defeat adj vector\$2) and (index adj process\$3) and (defect adj (region\$2 or area\$2 or zone\$2)) and (bas\$3 adj pattern\$2) and (window adj grid)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:45
L12	0	(systematic adj defect\$2) and (circuit adj design) and (feature adj vector\$2) and (defeat adj vector\$2) and (index adj process\$3) and (defect adj (region\$2 or area\$2 or zone\$2)) and (basis adj pattern\$2) and (window adj grid)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:46
L13	2	(systematic adj defect\$2) and (circuit adj design) and (feature adj vector\$2) and (index adj process\$3) and (defect adj (region\$2 or area\$2 or zone\$2))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:47
L14	1	(systematic adj defect\$2) and (circuit adj design) and (feature adj vector\$2) and (index adj process\$3) and (defect adj (region\$2 or area\$2 or zone\$2)) and (window adj grid)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:49
L15	1	((systematic adj defect\$2) and (circuit adj design) and (feature adj vector\$2) and (index adj process\$3) and (defect adj (region\$2 or area\$2 or zone\$2)) and (window adj grid)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:49
S1	1126	716/21	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 12:11
S2	1524	716/19	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 10:35

EAST Search History

S3	3468	716/4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 10:35
S4	2590	716/5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/06 10:35

[Web](#) [Images](#) [Video](#) [News](#) [Maps](#) [Gmail](#) [more ▾](#)

[Sign in](#)

[Google](#)

("systematic defects")("circuit layout")("basis p

[Search](#)

[Advanced Search](#)
[Preferences](#)

Web

Did you mean: ("systematic defects")("circuit layout")(**"basic** patterns")("feature vectors")("defeat vector")

No standard web pages containing all your search terms were found.

Your search - ("**systematic defects**")("circuit layout")("basis patterns")("feature vectors")("defeat vector") - did not match any documents.

Suggestions:

- Make sure all words are spelled correctly.
- Try different keywords.
- Try more general keywords.
- Try fewer keywords.

©2007 Google - [Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

[Web](#) [Images](#) [Video](#) [News](#) [Maps](#) [Gmail](#) [more ▾](#)

[Sign in](#)

[Google](#)

("systematic defects")("circuit layout")(patterns)

[Advanced Search](#)
[Preferences](#)

Web

Tip: Try removing quotes from your search to get more results.

Your search - ("**systematic defects**")("**circuit layout**")(**patterns**)("**feature vectors**")("**defeat vectors**") - did not match any documents.

Suggestions:

- Make sure all words are spelled correctly.
- Try different keywords.
- Try more general keywords.
- Try fewer keywords.

©2007 Google - [Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

[Web](#) [Images](#) [Video](#) [News](#) [Maps](#) [Gmail](#) [more ▾](#)

[Sign in](#)

[Google](#)

("circuit layout")(patterns)("feature vectors")("d

[Advanced Search](#)
[Preferences](#)

Web

Tip: Try removing quotes from your search to get more results.

Your search - **("circuit layout")(patterns)("feature vectors")("defeat vectors") "locating systematic defects"** - did not match any documents.

Suggestions:

- Make sure all words are spelled correctly.
- Try different keywords.
- Try more general keywords.
- Try fewer keywords.

©2007 Google - [Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

[Web](#) [Images](#) [Video](#) [News](#) [Maps](#) [Gmail](#) [more ▾](#)

[Sign in](#)

[Google](#)

(circuit)(shapes)(layout)("feature vectors") "loc

[Advanced Search](#)
[Preferences](#)

Web Results 1 - 1 of 1 for **(circuit)(shapes)(layout)("feature vectors") "locating systematic defects"**. (0.1

Tip: Try removing quotes from your search to get more results.

SYSTEM FOR SEARCH AND ANALYSIS OF SYSTEMATIC DEFECTS IN INTEGRATED ...

Disclosed is a method of **locating systematic defects** in integrated circuits. ... comprising:
transforming **shapes** in a **circuit layout** into **feature vectors**; ...

www.freepatentsonline.com/20050094863.html - 47k - [Cached](#) - [Similar pages](#)

Download [Google Pack](#): free essential software for your PC

(circuit)(shapes)(layout)("feature vec

[Search within results](#) | [Language Tools](#) | [Search Tips](#) | [Dissatisfied? Help us improve](#)

©2007 Google - [Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

[Web](#) [Images](#) [Video](#) [News](#) [Maps](#) [Gmail](#) [more ▾](#)

[Sign in](#)

[Google](#)

("systematic defects")(circuit)(shapes)(layout)(

[Search](#)

[Advanced Search](#)
[Preferences](#)

Web Results 1 - 1 of 1 for ("**systematic defects**")(**circuit**)(**shapes**)(**layout**)("**feature vectors**")(**window**)(**gri**

Tip: Try removing quotes from your search to get more results.

SYSTEM FOR SEARCH AND ANALYSIS OF SYSTEMATIC DEFECTS IN INTEGRATED ...

The invention transforms **shapes** in a each **window** into **feature vectors** by ... and said **shapes** in said **circuit layout**; and comparing said **feature vectors** to ...

www.freepatentsonline.com/20050094863.html - 47k - [Cached](#) - [Similar pages](#)

Download [Google Pack](#): free essential software for your PC

("systematic defects")(circuit)(shape

[Search](#)

[Search within results](#) | [Language Tools](#) | [Search Tips](#) | [Dissatisfied? Help us improve](#)

©2007 Google - [Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) |

Welcome United States Patent and Trademark Office

[Search Results](#)[BROWSE](#)[SEARCH](#)[IEEE XPLORE GUIDE](#)

Results for "(((circuit layout) <and> (systematic defects) <and> (feature vectors) <and> (index...)"

☒ e-mail

Your search matched 0 documents.

A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order.

» Search Options

[View Session History](#)[New Search](#)

Modify Search

(((circuit layout) <and> (systematic defects) <and> (feature vectors) <and> (index))<i>

☐ Check to search only within this results setDisplay Format: ☒ Citation ☐ Citation & Abstract

» Key

IEEE JNL IEEE Journal or Magazine

IET JNL IET Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IET CNF IET Conference Proceeding

IEEE STD IEEE Standard

No results were found.

Please edit your search criteria and try again. Refer to the Help pages if you need assistance with your search.

[Help](#) [Contact Us](#) [Privacy & Policy](#)

© Copyright 2006 IEEE – All Rights Reserved

Indexed by

